- Meet or Exceed the Requirements of TIA/EIA-422-B, TIA/EIA-485-A<sup>†</sup> and **ITU Recommendation V.11**
- **High-Speed Advanced Low-Power Schottky** Circuitry
- **Designed for 25-Mbaud Operation in Both** Serial and Parallel Applications
- Low Skew Between Devices . . . 6 ns Max
- **Low Supply-Current Requirements** ... 30 mA Max
- Individual Driver and Receiver I/O Pins With **Dual V<sub>CC</sub> and Dual GND**
- **Wide Positive and Negative Input/Output Bus Voltage Ranges**
- Driver Output Capacity . . . ±60 mA
- **Thermal Shutdown Protection**
- **Driver Positive- and Negative-Current** Limiting
- Receiver Input Impedance . . . 12 k $\Omega$  Min
- Receiver Input Sensitivity . . . ±200 mV Max
- Receiver Input Hysteresis . . . 60 mV Typ
- Operate From a Single 5-V Supply
- Glitch-Free Power-Up and Power-Down **Protection**

#### (TOP VIEW) 14 🛮 V<sub>CC</sub> NCΓ R **1** 2 13 V<sub>CC</sub> RE∏3 12 **[**] A DE¶4 11 **∏** B D[] 5 10 **∏** Z GND ∏ 6 9 🛮 Y GND ∏ 7 8 ∏ NC

D OR N PACKAGE

NC - No internal connection

# description

The SN65ALS180 and SN75ALS180 differential driver and receiver pairs are monolithic integrated circuits designed for bidirectional data communication on multipoint bus-transmission lines. They are designed for balanced transmission lines and meet TIA/EIA-422-B, TIA/EIA-485-A, and ITU Recommendation V.11.

The SN65ALS180 and SN75ALS180 combine a 3-state differential line driver and a differential input line receiver, both of which operate from a single 5-V power supply. The driver and receiver have active-high and active-low enables, respectively, that can be connected together externally to function as a direction control. The driver differential outputs and the receiver differential inputs are connected to separate terminals for greater flexibility and are designed to offer minimum loading to the bus when the driver is disabled or  $V_{CC} = 0$ .

These ports feature wide positive and negative common-mode voltage ranges, making the device suitable for party-line applications.

The SN65ALS180 is characterized for operation from -40°C to 85°C. The SN75ALS180 is characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

† These devices meet or exceed the requirements of TIA/EIA-485-A, except for the Generator Contention Test (para. 3.4.2) and the Generator Current Limit (para. 3.4.3). The applied test voltage ranges are -6 V to 8 V for the SN75ALS180 and -4 V to 8 V for the SN65ALS180.



#### **Function Tables**

#### **DRIVER**

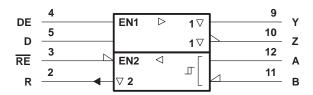
INPUT	ENABLE	OUTI	PUTS
D	DE	Υ	Z
Н	Н	Н	L
L	Н	L	Н
Х	L	Z	Z

#### **RECEIVER**

DIFFERENTIAL INPUTS A-B	ENABLE RE	OUTPUT R
V <sub>ID</sub> ≥ 0.2 V	L	Н
$-0.2 \text{ V} < \text{V}_{\text{ID}} < 0.2 \text{ V}$	L	?
$V_{ID} \le -0.2 V$	L	L
X	Н	z
Open	L	Н

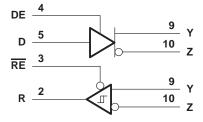
H = high level, L = low level, ? = indeterminate, X = irrelevant, Z = high impedance (off)

# logic symbol†

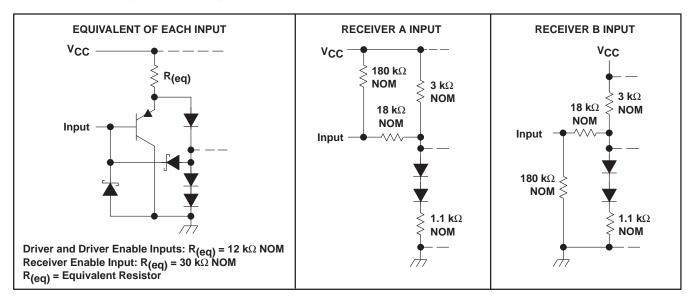


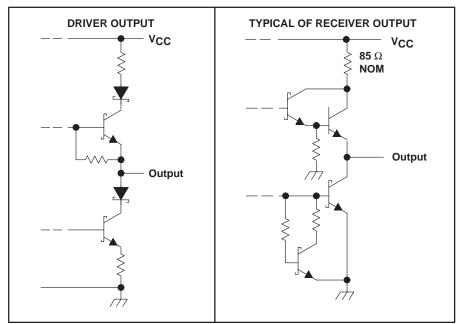
<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



#### schematics of inputs and outputs





# SN65ALS180, SN75ALS180 DIFFERENTIAL DRIVER AND RECEIVER PAIRS

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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub> (see Note 1)	7 V
Voltage range at any bus terminal	$\dots$ –10 V to 15 V
Enable input voltage, V <sub>I</sub>	5.5 V
Package thermal impedance, θ <sub>JA</sub> (see Note 2): D package	86°C/W
N package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T <sub>st</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		4.75	5	5.25	V
Voltage at any bus terminal (separately or common mode). Vuor Vuo				12	V
voltage at any bus terminal (separately of common mode), v) of v)C	Voltage at any bus terminal (separately or common mode), V <sub>I</sub> or V <sub>IC</sub>			-7	V
High-level input voltage, V <sub>IH</sub>	D, DE, and RE	2			V
Low-level input voltage, V <sub>IL</sub>	D, DE, and RE			0.8	V
Differential input voltage, V <sub>ID</sub> (see Note 3)				±12	V
High-level output current, IOH	Driver			-60	mA
I riigir-iever odiput current, iOH	Receiver			-400	μΑ
Low-level output current, IOI	Driver			60	mA
Low-level output current, IOL	Receiver			8	IIIA
Operating free air temperature Te	SN65ALS180	-40		85	°C
Operating free-air temperature, T <sub>A</sub>	SN75ALS180	0		70	J

NOTE 3: Differential-input/output bus voltage is measured at the noninverting terminal, A/Y, with respect to the inverting terminal, B/Z.



NOTES: 1. All voltage values, except differential I/O bus voltage, are with respect to network ground terminal.

<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51.

#### **DRIVERS**

# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CO	ONDITIONS†	MIN	TYP‡	MAX	UNIT	
VIK	Input clamp voltage	I <sub>I</sub> = -18 mA				-1.5	V	
Vo	Output voltage	IO = 0		0		6	V	
V <sub>OD1</sub>	Differential output voltage	IO = 0		1.5		6	V	
IVOD2I	Differential output voltage	$R_L = 100 \Omega$ ,	See Figure 1	1/2 V <sub>OD1</sub> or 2§			V	
		$R_L = 54 \Omega$ ,	See Figure 1	1.5	2.5	5		
V <sub>OD3</sub>	Differential output voltage	$V_{test} = -7 V to 12 V$ ,	See Figure 2	1.5		5	V	
Δ V <sub>OD</sub>	Change in magnitude of differential output voltage¶	$R_L$ = 54 $\Omega$ or 100 $\Omega$ ,	See Figure 1			±0.2	V	
Voc	Common-mode output voltage	$R_L$ = 54 $\Omega$ or 100 $\Omega$ ,	See Figure 1			3 –1	V	
Δ V <sub>OC</sub>	Change in magnitude of common-mode output voltage¶	$R_L$ = 54 $\Omega$ or 100 $\Omega$ ,	See Figure 1			±0.2	V	
lo.	0.1.1.1.1	Output disabled	V <sub>O</sub> = 12 V			1	mA	
Ю	Output current	(see Note 4)	V <sub>O</sub> = -7 V			-0.8	IIIA	
Ι <sub>ΙΗ</sub>	High-level input current	V <sub>I</sub> = 2.4 V				20	μΑ	
I <sub>IL</sub>	Low-level input current	V <sub>I</sub> = 0.4 V				-400	μΑ	
		V <sub>O</sub> = -6 V	SN75ALS180			-250		
		V <sub>O</sub> = -4 V	SN65ALS180			-250		
los	Short-circuit output current#	V <sub>O</sub> = 0	All			-150	mA	
		AO = ACC	All			250		
		VO = 8 V	All			250		
Icc	Supply current	No load	Driver outputs enabled, Receiver disabled		25	30	mA	
			Outputs disabled		19	26	1	

<sup>†</sup> The power-off measurement in TIA/EIA-422-B applies to disabled outputs only and is not applied to combined inputs and outputs.

NOTE 4: This applies for both power on and off; refer to TIA/EIA-485-A for exact conditions. The TIA/EIA-422-B limit does not apply for a combined driver and receiver terminal.

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature

PARAMETER		TEST CONDITIONS		MIN	TYP‡	MAX	UNIT	
t <sub>d</sub> (OD)	Differential output delay time	$R_L = 54 \Omega$ ,	$C_L = 50 pF$ ,	See Figure 3	3	8	13	ns
	Pulse skew (  t <sub>d(ODH)</sub> - t <sub>d(ODL)</sub>  )	$R_L = 54 \Omega$ ,	$C_L = 50 pF$ ,	See Figure 3		1	6	ns
t <sub>t</sub> (OD)	Differential output transition time	$R_L = 54 \Omega$ ,	C <sub>L</sub> = 50 pF,	See Figure 3	3	8	13	ns
<sup>t</sup> PZH	Output enable time to high level	$R_L = 110 \Omega$ ,	See Figure 4			23	50	ns
tPZL	Output enable time to low level	$R_L = 110 \Omega$ ,	See Figure 5			19	24	ns
<sup>t</sup> PHZ	Output disable time from high level	$R_L = 110 \Omega$ ,	See Figure 4			8	13	ns
<sup>t</sup> PLZ	Output disable time from low level	$R_L = 110 \Omega$ ,	See Figure 5			8	13	ns

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$  and  $T_A = 25^{\circ}\text{C}$ .



<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

<sup>§</sup> The minimum  $V_{OD2}$  with  $100-\Omega$  load is either 1/2  $V_{OD2}$  or 2 V, whichever is greater.

<sup>¶ ∆|</sup>V<sub>OD</sub>| and ∆|V<sub>OC</sub>| are the changes in magnitude of V<sub>OD</sub> and V<sub>OC</sub>, respectively, that occur when the input is changed from a high level to a low level.

<sup>#</sup> Duration of the short circuit should not exceed one second for this test.

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#### **SYMBOL EQUIVALENTS**

DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A
Vo	V <sub>oa</sub> , V <sub>ob</sub>	V <sub>oa</sub> , V <sub>ob</sub>
IV <sub>OD1</sub> I	Vo	Vo
IV <sub>OD2</sub> I	$V_t (R_L = 100 \Omega)$	$V_t (R_L = 54 \Omega)$
IV <sub>OD3</sub> I		V <sub>t</sub> (test termination measurement 2)
V <sub>test</sub>		$V_{tst}$
Δ V <sub>OD</sub>	$  V_t  -  \overline{V}_t  $	$  V_t  -  \overline{V}_t  $
Voc	V <sub>os</sub>	V <sub>os</sub>
Δ VOC	$ V_{OS} - \overline{V}_{OS} $	$ V_{OS} - \overline{V}_{OS} $
los	I <sub>sa</sub>  ,  I <sub>sb</sub>	
IO	$ I_{xa} ,  I_{xb} $	l <sub>ia</sub> , l <sub>ib</sub>

#### **RECEIVERS**

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

	PARAMETER	TE	ST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>IT+</sub>	Positive-going input threshold voltage	V <sub>O</sub> = 2.7 V,	I <sub>O</sub> = -0.4 mA			0.2	V
V <sub>IT</sub> —	Negative-going input threshold voltage	V <sub>O</sub> = 0.5 V,	I <sub>O</sub> = 8 mA	-0.2‡			V
V <sub>hys</sub>	Hysteresis voltage (V <sub>IT+</sub> - V <sub>IT-</sub> )				60		mV
VIK	Enable-input clamp voltage	I <sub>I</sub> = -18 mA				-1.5	V
Vон	High-level output voltage	V <sub>ID</sub> = 200 mV,	$I_{OH} = -400 \mu\text{A}$ , See Figure 6	2.7			V
VOL	Low-level output voltage	$V_{ID} = -200 \text{ mV},$	I <sub>OL</sub> = 8 mA, See Figure 6			0.45	V
loz	High-impedance-state output current	$V_0 = 0.4 \text{ V to } 2.4 \text{ V}$				±20	μΑ
Ī.,	Line input current	Other input = 0 V	V <sub>I</sub> = 12 V			1	mA
l II	Line input current	(see Note 5)	V <sub>I</sub> = −7 V			-0.8	IIIA
lіН	High-level enable-input current	V <sub>IH</sub> = 2.7 V				20	μΑ
IIL	Low-level enable-input current	V <sub>IL</sub> = 0.4 V				-100	μΑ
rį	Input resistance			12			kΩ
los	Short-circuit output current	$V_{ID} = 200 \text{ mV},$	V <sub>O</sub> = 0	-15		-85	mA
Icc	Supply current	No load	Receiver outputs enabled, Driver inputs disabled		19	30	mA
		Outputs disabled		19	26		

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

NOTE 5: This applies for both power on and power off. Refer to TIA/EIA-485-A for exact conditions.



<sup>&</sup>lt;sup>‡</sup> The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for common-mode input voltage and threshold voltage levels only.

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature

PARAMETER		TEST CONDI	TIONS	MIN	TYP†	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$ See Figure 7	C <sub>L</sub> = 15 pF,	9	14	19	ns
tPHL	Propagation delay time, high- to low-level output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$ See Figure 7	C <sub>L</sub> = 15 pF,	9	14	19	ns
	Skew ( tpHL - tpLH )	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$ See Figure 7	C <sub>L</sub> = 15 pF,		2	6	ns
<sup>t</sup> PZH	Output enable time to high level	C <sub>L</sub> = 15 pF,	See Figure 8		7	14	ns
tPZL	Output enable time to low level	$C_L = 15 pF,$	See Figure 8		7	14	ns
t <sub>PHZ</sub>	Output disable time from high level	$C_L = 15 pF,$	See Figure 8		20	35	ns
t <sub>PLZ</sub>	Output disable time from low level	$C_L = 15 pF,$	See Figure 8		8	17	ns

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

#### PARAMETER MEASUREMENT INFORMATION

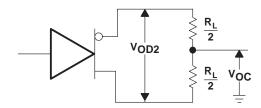


Figure 1. Driver  $V_{\mbox{\scriptsize OD}}$  and  $V_{\mbox{\scriptsize OC}}$ 

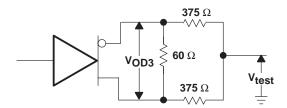
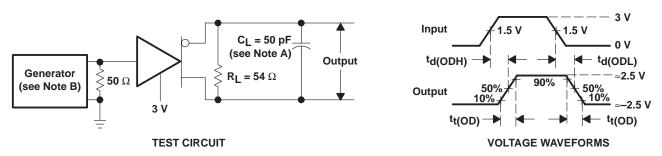


Figure 2. Driver V<sub>OD3</sub>

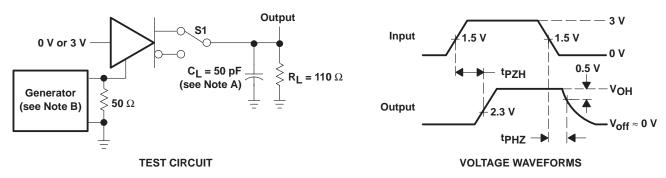
#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_{\Gamma} \leq$  6 ns,  $t_{f} \leq$  6 ns,  $t_{O} = 50 \Omega$ .

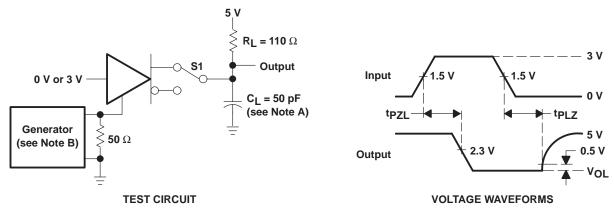
Figure 3. Driver Test Circuit and Voltage Waveforms



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_f \leq$  6 ns,  $t_f \leq$  8 ns,  $t_f \leq$  9 ns

Figure 4. Driver Test Circuit and Voltage Waveforms



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_{\Gamma} \leq$  6 ns,  $t_{\Gamma} \leq$  7 ns,  $t_{\Gamma} \leq$  8 ns,  $t_{\Gamma} \leq$  8 ns,  $t_{\Gamma} \leq$  9 ns,  $t_{\Gamma} \leq$ 

Figure 5. Driver Test Circuit and Voltage Waveforms



#### PARAMETER MEASUREMENT INFORMATION

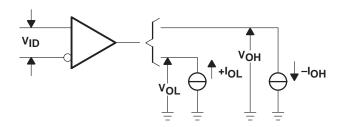
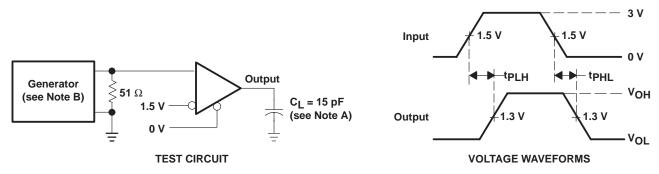


Figure 6. Receiver VOH and VOL

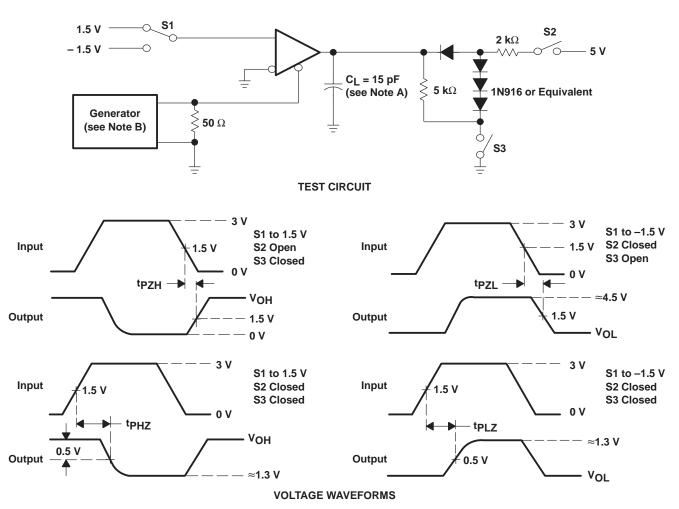


NOTES: A.  $C_L$  includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_r \leq$  6 ns,  $t_f \leq$  6 ns,  $Z_O = 50 \Omega$ .

Figure 7. Receiver Test Circuit and Voltage Waveforms

#### PARAMETER MEASUREMENT INFORMATION

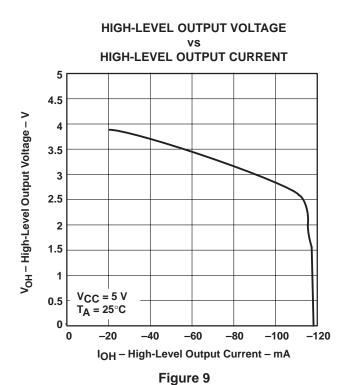


NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_{\Gamma} \leq$  6 ns,  $t_{f} \leq$  6 ns,  $t_{O} = 50 \Omega$ .

Figure 8. Receiver Test Circuit and Voltage Waveforms

#### TYPICAL CHARACTERISTICS - DRIVERS



LOW-LEVEL OUTPUT VOLTAGE
vs
LOW-LEVEL OUTPUT CURRENT

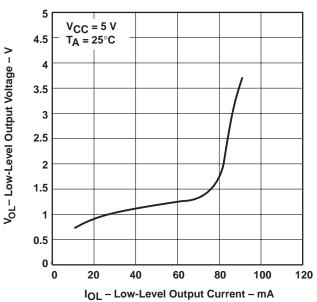


Figure 10

#### **DIFFERENTIAL OUTPUT VOLTAGE**

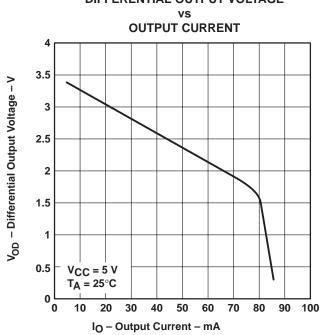
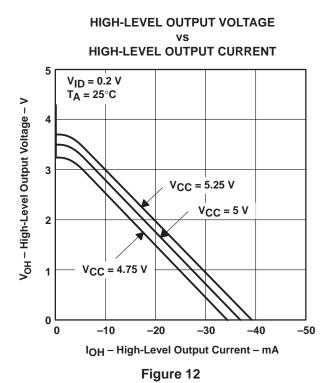
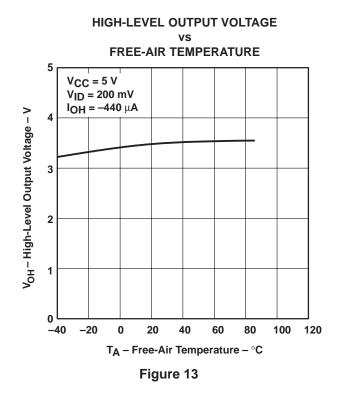


Figure 11

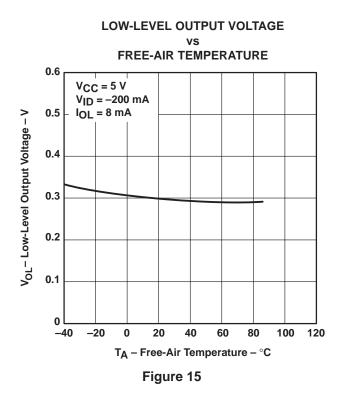
#### TYPICAL CHARACTERISTICS - RECEIVERS



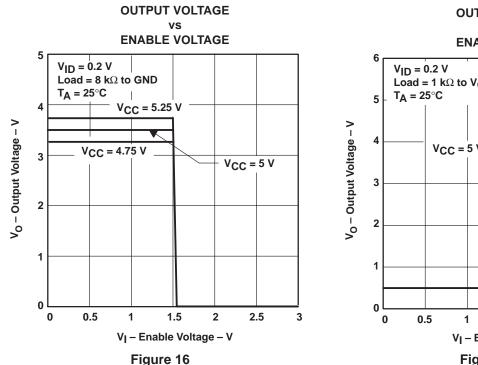


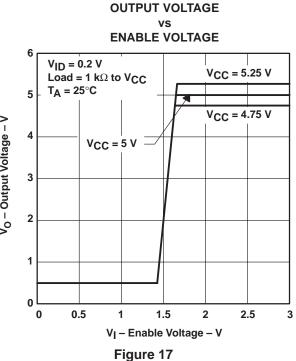
### LOW-LEVEL OUTPUT VOLTAGE LOW-LEVEL OUTPUT CURRENT 0.6 V<sub>CC</sub> = 5 V T<sub>A</sub> = 25°C $V_{ID} = -200 \text{ mV}$ 0.5 V<sub>OL</sub> - Low-Level Output Voltage - V 0.4 0.3 0.2 0.1 0 0 5 10 15 20 25 30 IOL - Low-Level Output Current - mA

Figure 14

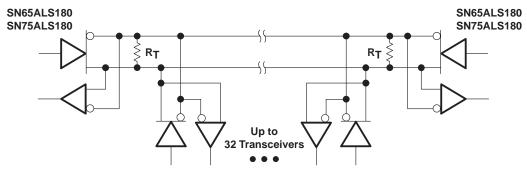


#### **TYPICAL CHARACTERISTICS - RECEIVERS**





#### **APPLICATION INFORMATION**



NOTE A: The line should terminate at both ends in its characteristic impedance (R<sub>T</sub> = Z<sub>O</sub>). Stub lengths off the main line should be kept as short as possible.

Figure 18. Typical Application Circuit

#### **IMPORTANT NOTICE**

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